Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/677,566	DEY ET AL.
Examiner	Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
370	208	6/8/2007	SJK	
370	203	6/8/2007	SJK	

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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	6/8/2007	SJK
Inventor name and Assignee search in PALM ExPO and EAST	6/8/2007	SJK
Consulted with Chau Nguyen (SPE)	6/8/2007	SJK
Google (www.google.com)	6/8/2007	SJK
(370/203.ccls. or 370/208.ccls. or 370/210.ccls. or 375/365.ccls. or 375/346.ccls.)	6/8/2007	SJK